

SLOVENSKI STANDARD
SIST EN 60068-2-69:2017**01-september-2017****Nadomešča:****SIST EN 60068-2-54:2006****SIST EN 60068-2-69:2008**

Okoljski preskusi - 2-69. del: Preskusi - Preskus Te/Tc: Preskus spajkanja elektronskih komponent in plošč tiskanih vezij z metodo za določanje omočljivosti (merjenje sile)

Environmental testing - Part 2-69: Tests - Test Te/Tc: Solderability testing of electronic components and printed boards by the wetting balance (force measurement) method

Umgebungseinflüsse - Teil 2-69: Prüfungen - Prüfung Te: Prüfung der Lötbarkeit von Bauelementen der Elektronik für Oberflächenmontage (SMD) mit der Benetzungswaage

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Essais d'environnement - Partie 2-69: Essais - Essai Te: Essai de brasabilité des composants électroniques pour les composants montés en surface (CMS) par la méthode de la balance de mouillage

Ta slovenski standard je istoveten z: EN 60068-2-69:2017

ICS:

19.040	Preskušanje v zvezi z okoljem	Environmental testing
31.190	Sestavljeni elektronski elementi	Electronic component assemblies

SIST EN 60068-2-69:2017**en**

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EUROPEAN STANDARD

EN 60068-2-69

NORME EUROPÉENNE

EUROPÄISCHE NORM

June 2017

ICS 19.040; 31.190

Supersedes EN 60068-2-54:2006, EN 60068-2-69:2007

English Version

Environmental testing -
Part 2-69: Tests - Test Te/Tc: Solderability testing of electronic
components and printed boards by the wetting balance (force
measurement) method
(IEC 60068-2-69:2017)

Essais d'environnement -
Partie 2-69: Essais - Essai Te/Tc: Essai de brasabilité des
composants électroniques et cartes imprimées par la
méthode de la balance de mouillage (mesure de la force)
(IEC 60068-2-69:2017)

Umgebungseinflüsse - Teil 2-69: Prüfungen - Prüfung
Te/TC: Prüfung der Lötbarkeit von Bauelementen der
Elektronik und Leiterplatten mit der Benetzungswaage
(Kraftmessung)
(IEC 60068-2-69:2017)

This European Standard was approved by CENELEC on 2017-04-11. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

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This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

EN 60068-2-69:2017**European foreword**

The text of document 91/1405/FDIS, future edition 3 of IEC 60068-2-69, prepared by IEC/TC 91 "Electronics assembly technology" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 60068-2-69:2017.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2018-01-11
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2020-04-11

This document supersedes EN 60068-2-69:2007 and EN 60068-2-54:2006.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC shall not be held responsible for identifying any or all such patent rights.

Endorsement notice

The text of the International Standard IEC 60068-2-69:2017 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60068-3-13:2016	NOTE	Harmonized as EN 60068-3-13:2016 (not modified).
IEC 61190-1-1:2002	NOTE	Harmonized as EN 61190-1-1:2002 (not modified).
ISO 9453:2014	NOTE	Harmonized as EN ISO 9453:2014 (not modified).

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-1	-	Environmental testing - Part 1: General and guidance	EN 60068-1	-
IEC 60068-2-2	-	Environmental testing - Part 2-2: Tests - Test B: Dry heat	EN 60068-2-2	-
IEC 60068-2-20	2008	Environmental testing - Part 2-20: Tests - Test T: Test methods for solderability and resistance to soldering heat of devices with leads.	EN 60068-2-20	2008
IEC 60068-2-66	-	Environmental testing - Part 2-66: Test methods - Test Cx: Damp heat, steady state (unsaturated pressurized vapour)	EN 60068-2-66	-
IEC 61190-1-3	2007	Attachment materials for electronic assembly - Part 1-3: Requirements for electronic grade solder alloys and fluxed and non-fluxed solid solders for electronic soldering applications	EN 61190-1-3	2007
+A1	2010		+A1	2010
ISO 683	Series	Heat treatable steels, alloy steels and free-cutting steels	EN ISO 683	Series ¹⁾
ISO 6362	Series	Wrought aluminium and aluminium alloys extruded rods/bars, tubes and profiles	-	-

¹⁾ At draft stage.

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IEC 60068-2-69

Edition 3.0 2017-03

INTERNATIONAL STANDARD

NORME INTERNATIONALE

Environmental testing –
Part 2-69: Tests – Test Te/Tc: Solderability testing of electronic components
and printed boards by the wetting balance (force measurement) method

Essais d'environnement –
Partie 2-69: Essais – Essai Te/Tc: Essai de brasabilité des composants
électroniques et cartes imprimées par la méthode de la balance de mouillage
(mesure de la force)

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

ENVIRONMENTAL TESTING –

**Part 2-69: Tests – Test Te/Tc: Solderability testing of
electronic components and printed boards
by the wetting balance (force measurement) method**

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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International Standard IEC 60068-2-69 has been prepared by IEC technical committee 91: Electronics assembly technology.

This third edition cancels and replaces the second edition published in 2007 as well as the second edition of IEC 60068-2-54 published in 2006 and constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- integration of IEC 60068-2-54;
- inclusion of tests of printed boards;
- inclusion of new component types, and updating test parameters for the whole component list;

- inclusion of a new gauge R & R test protocol to ensure that the respective wetting balance equipment is correctly calibrated.

The text of this standard is based on the following documents:

FDIS	Report on voting
91/1405/FDIS	91/1426/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 60068 series, under the general title *Environmental testing*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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ENVIRONMENTAL TESTING –

Part 2-69: Tests – Test Te/Tc: Solderability testing of electronic components and printed boards by the wetting balance (force measurement) method

1 Scope

This part of IEC 60068 outlines test Te/Tc, the solder bath wetting balance method and the solder globule wetting balance method to determine, quantitatively, the solderability of the terminations. Data obtained by these methods are not intended to be used as absolute quantitative data for pass–fail purposes.

The procedures describe the solder bath wetting balance method and the solder globule wetting balance method. They are applicable to components and printed boards with metallic terminations and metallized solder pads.

This document provides the measurement procedures for solder alloys both with and without lead (Pb).

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2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60068-1, *Environmental testing – Part 1: General and guidance*

IEC 60068-2-2, *Environmental testing – Part 2-2: Tests – Test B: Dry heat*

IEC 60068-2-20:2008, *Environmental testing – Part 2-20: Tests – Test T: Test methods for solderability and resistance to soldering heat of devices with leads*

IEC 60068-2-66, *Environmental testing – Part 2: Test methods – Test Cx: Damp heat, steady state (unsaturated pressurized vapour)*

IEC 61190-1-3:2007, *Attachment materials for electronic assembly – Part 1-3: Requirements for electronic grade solder alloys and fluxed and non-fluxed solid solders for electronic soldering applications*

IEC 61190-1-3:2007/AMD1:2010

ISO 683 (all parts), *Heat-treatable steels, alloy steels and free-cutting steels*

ISO 6362 (all parts), *Wrought aluminium and aluminium alloys – Extruded rods/bars, tubes and profiles*

3 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 60068-1 and IEC 60068-2-20 apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

4 General description of the method

4.1 General

The user should note that the test method specified in this document is intended to provide consistent and discriminatory data between various test sites. Hence the choice of alloy, temperature and flux shall be controlled.

Using this test method to control a production process is encouraged. However, as each production process will employ different alloys, temperatures and fluxes, such test results shall be agreed upon between user and supplier. In case of a dispute, the procedures of this document shall prevail.

NOTE Information regarding wetting balance for SMD solderability testing is described in Annex B.

4.2 Components

The test specimen shall be a sample from the intended production batch. The test specimen is mounted into a suitable holder that is suspended from a sensitive balance. Liquid flux is then applied to the specimen that is brought into contact with the cleaned surface of the liquid solder within a solder bath, or the apex of a solder globule. The solder in either case is at a controlled temperature, and the lead or termination under test is immersed to the prescribed depth.

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4.3 Printed boards

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The test specimen should be a representative test specimen, a portion of the printed board being tested, or a whole board if within size limits, such that an immersion depth defined in the individual method is possible. Test specimens may be used for rigid board surface solderability and plated-through-hole solderability.

Liquid flux is then applied to the specimen that is brought into contact with the cleaned surface of a solder bath, or the apex of a solder globule, that is at a controlled temperature and immersed to the prescribed depth.

4.4 Measurement

The resultant forces, measured in mN, of buoyancy and surface tension acting upon the immersed termination are detected by a transducer and converted into a signal that is continuously monitored as a function of time, and recorded and displayed on a computer screen.

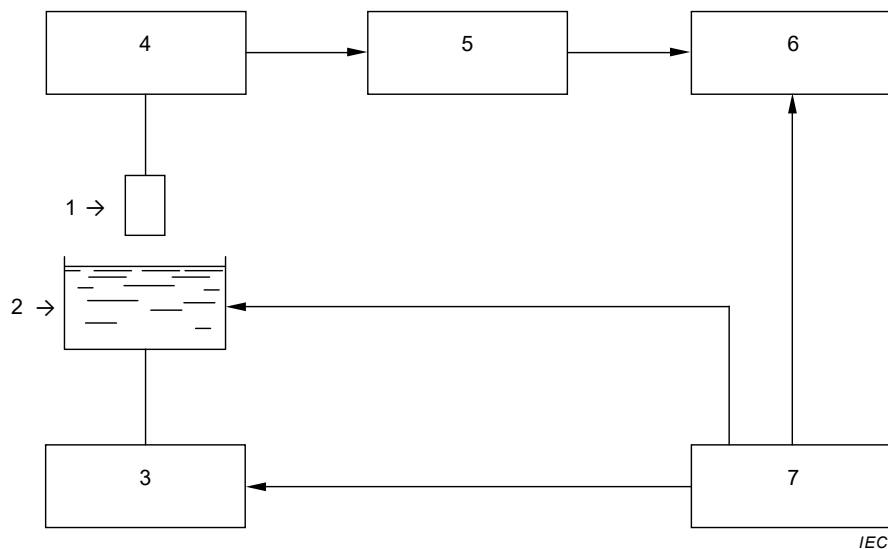
The wetting speed and the extent of wetting are derived from the force against time curve. The trace may be compared with that derived from a perfectly wetted specimen of the same nature and dimensions.

5 Description of the test apparatus

Figure 1 and Figure 2 show a suitable arrangement for the test apparatus.

The apparatus specifications are given in Annex A.

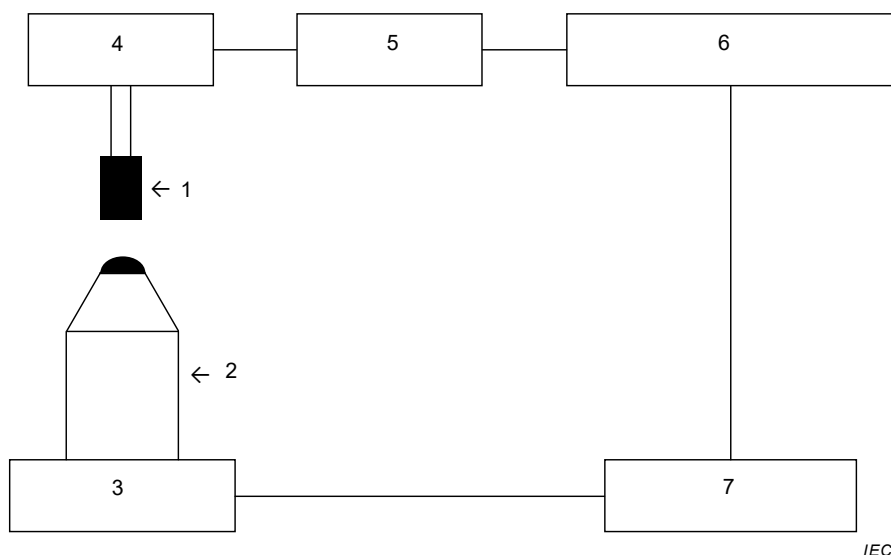
The specimen is suspended from a sensitive balance and a mechanism used to either raise the solder to meet the specimen or lower the specimen into the solder. After conditioning, the transducer signal is passed to a computer, where the force against time curve may be displayed and analysed.

**Key**

- | | | | |
|---|-------------------------------|---|------------------------|
| 1 | Specimen | 2 | Solder bath |
| 3 | Solder bath lifting mechanism | 4 | Balance and transducer |
| 5 | Signal conditioner | 6 | Computer |
| 7 | Control box | | |

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Figure 1 – Arrangement for the test apparatus (solder bath wetting balance method)

**Key**

- | | | | |
|---|--------------------|---|------------------------|
| 1 | Specimen | 2 | Globule block |
| 3 | Lift mechanism | 4 | Balance and transducer |
| 5 | Signal conditioner | 6 | Computer |
| 7 | Control box | | |

Figure 2 – Arrangement for the test apparatus (solder globule wetting balance method)